

# **MP300** CL3



A manufacturing tester for all types of contactless objects

# The MP300 CL3 Advantage

The MP300 CL3 capitalises on the success of its predecessors MP300 CL2 and MT1 to offer to the market a high end production tester for contactless objects. This tool brings further the test functions of its ancestors, and adds the possibility to perform all necessary tests to ensure of the quality of a NFC phone, in all modes (reader and card simulation modes).



The MP300 range of products is based on a mother board (MP300 UC1) which can host up to 4 different modules.

By mixing different modules together on the same mother board, it is possible to build customized configurations to fit your exact needs.



More combinaisons available on demand



## The Ideal Tool

#### Supported Protocols

- ISO/IEC 14443-3 (proximity cards) (Type A/B)
- B' (InnovatronTM)
- ISO/IEC 15693 (vicinity cards)
- ISO 18000-3 Mode 1 .
- Mifare TM
- FeliCaTM
- NFC Forum modes

- NFC Forum tags
- ISO 18092 (NFC-IP1)
- WPC (Qi)
- Raw mode: implementation of custom protocols and support of out of standard chips

#### Programmable parameters

- Physical parameters
- Field strength, modulation index, rise & fall times
- Logical parameters
- Type A pause, FWT, type B framing, communication speed

#### Available tests

Electrical testing

- Resonance frequency measurement / Q factor
- Complex impedance (chip/antenna)
- Magnetic field measurement
- Measurement of the power generated by the **Base Station**

#### **Key Points**

- Compatible with ISO/IEC 14443-3 and -4, ISO/IEC 15693, Mifare™, FeliCa™, Innovatron™ specifications
- Full management of the T=CL protocol
- Supports the highest bitrates (up to 848kbps by default, up to 6.8Mbps with the VHBR option)
- All physical parameters adjustable (field strength, carrier frequency, modulation index, rise and fall time of the modulation, ...)
- Advanced logical test features (response time measurement, modulation (positive/negative), short time between two commands, ...)
- Advanced electrical measurement features: chip impedance, resonance frequency, Q factor of a smartcard, load modulation of a chip
- Supports both terminal and smartcard simulation: the • tool tests all modes of a NFC device using the same test antenna
- Supports test of WPC compatible devices in production, in conjunction or independently from the NFC interface.

#### **BUSINESS AREAS**















F-ID

(Driver licences,

ID cards...)



WPC



Telecom

Banking E-health

Contact micro-Module USB Stick enabled U-SIM

NFC E-Passeport

Mastercard CQM Testina



M2M

#### Supported protocols

ISO/IEC 14443-3 (proximity cards) (Type A	VB)				
Supported data rates:	- 106, 212, 424, 848 kbps				
	- Asymetrical data rates supported				
	- VHBR DSK 2 PSR				
B' (Innovatron™)					
ISO/IEC 15693 (vicinity cards) ISO/IEC 156	393 (vicinity cards)				
Supported communication speeds:	Low & high data dates, 1 out of 4 & 1 out of 256				
ISO 18000-3 Mode 1					
Mifare TM					
Types supported:	Classic, Light, Ultra Light, Ultra Light C,				
FeliCa ™					
Available data rates: 212 and 424 kbps					
NFC Forum modes	Peer2Peer				
	Listening				
	Polling				
NFC Forum tags					
Types supported: Tag types 1,2,3,4					
ISO 18092 (NFC-IP1)					
Modes supported: Active/passive mode, in	n both Initiator/Target variantes				
WPC (Qi)					
Simulation of Mobile device, and Base sta	tion				
Raw mode: implementation of custom pro	stocols and support of out of standard chips				

#### Programmable parameters

Physical Parameters		
- Field strength		
- Modulation index		
- Rise & fall times		
Logical Parameters		
-Type A pause		
- FWT		
- Type B framing - Communication speed		
- Communication speed		

#### Available tests

Electrical testing

- Resonance frequency measurement/Q factor
- Complex impedence (chip/antenna)
- Magnetic field measurement
- Measurement of the power generated by the Base station

### NI Services and Support

- Maintenance contracts :
  - Firmware/software updates
  - Hardware repair
  - Onsite customer support
  - Replacement tool
- Technical support located in Asia, Europe and Americas
- Training courses customizable :
  - knowledge level based
  - Time constraints
  - Topics of interest
- Debug and pre-certification of contact and contactless devices



서울본사

 서울특별시 영등포구 경인로 775(문래동 3가, 에이스하이테크시티 3동 2층 201호)

 TEL: 070-7872-0701
 FAX: 02-2167-3801
 E-mail: sales@nubicom.co.kr

대전지사

**대전광역시 유성구 덕명동로 22번길 10** TEL: 070-7872-0712 FAX: 02-2167-**380**1

mail: jbkim@nubicom.co.kr